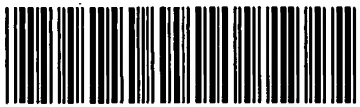


<b>Search Notes</b>  	<b>Application/Control No.</b>  10544271	<b>Applicant(s)/Patent Under Reexamination</b>  YOO ET AL.
	<b>Examiner</b>  Kim, Jay C	<b>Art Unit</b>  2815

SEARCHED			
Class	Subclass	Date	Examiner
257	E33.025, E33.028, E33.03, E33.033	6/28/07	J.K.
257	77, 85	7/9/07	J.K.

SEARCH NOTES		
Search Notes	Date	Examiner
EAST (US-PGPUB; USPAT; USOCR), See EAST Search History	6/22/07	J.K.
EAST (US-PGPUB; USPAT; USOCR), See EAST Search History	6/28/07	J.K.
EAST (DERWENT; EPO; JPO), See EAST Search History	6/28/07	J.K.
EAST (US-PGPUB; USPAT; USOCR), See EAST Search History	7/9/07	J.K.
EAST (US-PGPUB; USPAT; USOCR), See EAST Search History	7/27/07	J.K.
EAST (US-PGPUB; USPAT; USOCR), See EAST Search History	7/29/07	J.K.
EAST (US-PGPUB; USPAT; USOCR), See EAST Search History	7/30/07	J.K.

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner